

Resource Summary Report

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Zeiss: Crossbeam 550 with Leica VCT 500 Cryo-Suite

RRID:SCR_028555

Type: Tool

Proper Citation

Zeiss: Crossbeam 550 with Leica VCT 500 Cryo-Suite (RRID:SCR_028555)

Resource Information

URL: <https://em-lab.berkeley.edu/EML/zeiss-xb-550-sem>

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Description: Zeiss Crossbeam 550 (sometimes referred to as the XB 550) is dual-beam system that combines the Gemini 2 SEM with the Ion-sculptor FIB (Focused Ion Beam) for advanced materials analysis and sample preparation. XB 550 combined with the Leica EM VCT 500 is a highly specialized system designed for advanced cryogenic workflows in materials and life sciences. It enables researchers to investigate and prepare samples at ultra-low temperatures without exposing them to air or contamination.

Synonyms: , Zeiss XB 550 with Leica VCT 500 Cryo-Suite system, Berkeley EML Zeiss Crossbeam 550 with Leica VCT 500 Cryo-Suite system

Resource Type: instrument resource

Keywords: focused ion beam; FIB-SEM; electron microscope; scanning; SEM; VolumeEM; array tomography; high-resolution

Funding: NIH 1S10OD030258-01

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028555.pdf , https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/Leica%20SCR_028555.pdf

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Alternate URLs: <https://www.zeiss.com/microscopy/us/products/sem-fib-sem/fib-sem/crossbeam-550.html>

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Record Last Update: 20260815T183317+0000

Ratings and Alerts

No rating or validation information has been found for Zeiss: Crossbeam 550 with Leica VCT 500 Cryo-Suite.

No alerts have been found for Zeiss: Crossbeam 550 with Leica VCT 500 Cryo-Suite.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.